

<b>Features</b> <ul style="list-style-type: none"> <li>➤ Split Gate Trench MOSFET technology</li> <li>➤ Excellent package for heat dissipation</li> <li>➤ High density cell design for low RDS(ON)</li> </ul>	<b>Bvdss</b>	<b>Rdson</b>	<b>ID</b>
	<b>30V</b>	<b>1.4mΩ</b>	<b>150A</b>
	<b>Application</b> <ul style="list-style-type: none"> <li>➤ DC-DC converter</li> <li>➤ Power management functions</li> <li>➤ Synchronous-rectification applications</li> </ul>		
<b>Package</b> <div style="display: flex; justify-content: space-around; align-items: flex-end;"> <div style="text-align: center;">               1. Marking and pin assignment         </div> <div style="text-align: center;">               2. PDFN3*3-8L top view         </div> <div style="text-align: center;">               3. Schematic diagram         </div> </div>			

**Package Marking and Ordering Information**

Device Marking	Device	Device Package	Quantity
150N03	S150N03D	PDFN3*3-8L	5000

**Absolute Maximum Ratings** (T<sub>c</sub>=25°C unless otherwise specified)

Parameter	Symbol	Value	Unit	
Drain-Source Voltage	V <sub>DS</sub>	30	V	
Gate-Source Voltage	V <sub>GS</sub>	±20	V	
Continuous Drain Current V <sub>GS</sub>	(T <sub>c</sub> = 25°C)	I <sub>D</sub>	150	A
	(T <sub>c</sub> = 100°C)	I <sub>D</sub>	95	A
Pulsed Drain Current (1)	I <sub>DM</sub>	600	A	
Single Pulsed Avalanche Energy (2)	E <sub>AS</sub>	180	mJ	
Power Dissipation	P <sub>d</sub>	66	W	
Junction Temperature	T <sub>J</sub>	-55~+150	°C	
Storage Temperature	T <sub>STG</sub>	-55~+150	°C	

**Thermal Resistance Ratings**

Parameter	Symbol	Value	Unit
Junction to case	R <sub>θJC</sub>	1.9	°C/W
Junction to ambient (3)	R <sub>θJA</sub>	60	°C/W



## Ordering Information

Ordering Number	Package	Pin Assignment			Packing
		G	D	S	
Halogen Free					
HLS150N03D	PDFN3*3-8L	4	5,6,7,8	1,2,3	Tape Reel

Electrical Characteristics (T<sub>J</sub> = 25°C, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	30	-	-	V
Gate-body Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
Zero Gate Voltage Drain Current	T <sub>J</sub> =25° C	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V	-	-	1	μA
	T <sub>J</sub> =100° C		-	-	100	
Gate-Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.2	1.7	2.2	V
Drain-Source On-Resistance (4)	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A	-	1.4	1.9	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 15A	-	2.1	2.8	
Forward Transconductance (4)	g <sub>fs</sub>	V <sub>DS</sub> = 10V, I <sub>D</sub> = 20A	-	85	-	S
<b>Dynamic Characteristics (5)</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V, f = 1MHz	-	2554	-	pF
Output Capacitance	C <sub>oss</sub>		-	924	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	73.5	-	
Gate Resistance	R <sub>g</sub>	f = 1MHz	-	0.98	-	Ω
<b>Switching Characteristics (5)</b>						
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 15V, I <sub>D</sub> = 20A	-	39.1	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	6.7	-	
Gate-Drain Charge	Q <sub>gd</sub>		-	5.9	-	
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>GS</sub> = 10V, V <sub>DD</sub> = 15V, R <sub>G</sub> = 3Ω, I <sub>D</sub> = 20A	-	10	-	ns
Rise Time	t <sub>r</sub>		-	7.3	-	
Turn-Off Delay Time	t <sub>d(off)</sub>		-	38.6	-	
Fall Time	t <sub>f</sub>		-	16.4	-	



Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> =20A, di/dt=100A/μs	-	27	-	nC
Body Diode Reverse Recovery Time	t <sub>rr</sub>		-	54	-	ns
<b>Drain-Source Body Diode Characteristics</b>						
Diode Forward Voltage (4)	V <sub>SD</sub>	I <sub>S</sub> = 20A, V <sub>GS</sub> = 0V	-	-	1.2	V
Continuous Source Current	TC=25° C	I <sub>S</sub>	-	-	150	A

**Notes:**

1. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub>=150° C.
2. The test condition is V<sub>DD</sub>=25V, V<sub>GS</sub>=10V, L=0.4mH, I<sub>AS</sub>=30A.
3. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper, The value in user's specific board design.
4. The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%.
5. This value is guaranteed by design hence it is not included in the production test.



### Typical Characteristics

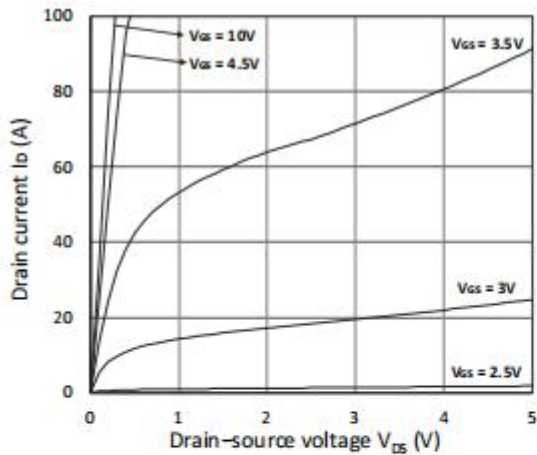


Figure 1. Output Characteristics

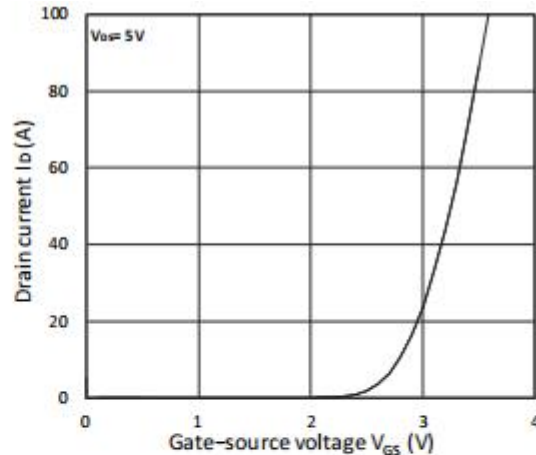


Figure 2. Transfer Characteristics

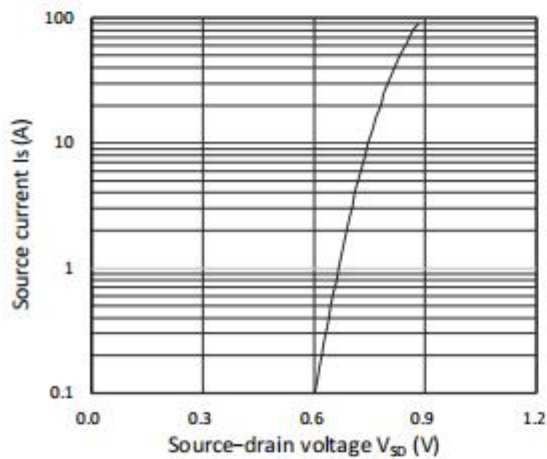


Figure 3. Forward Characteristics of Reverse

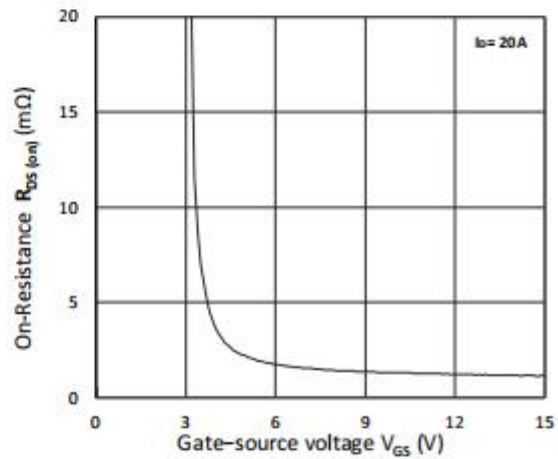


Figure 4.  $R_{DS(on)}$  vs.  $V_{GS}$

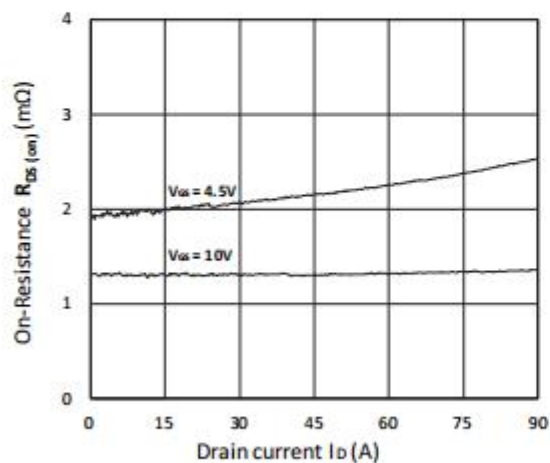


Figure 5.  $R_{DS(on)}$  vs.  $I_D$

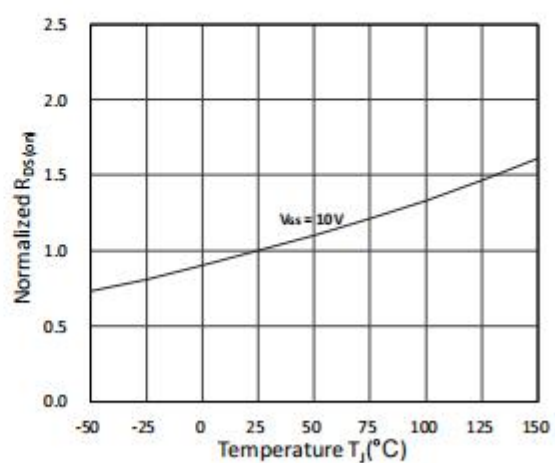


Figure 6. Normalized  $R_{DS(on)}$  vs. Temperature



### Typical Characteristics

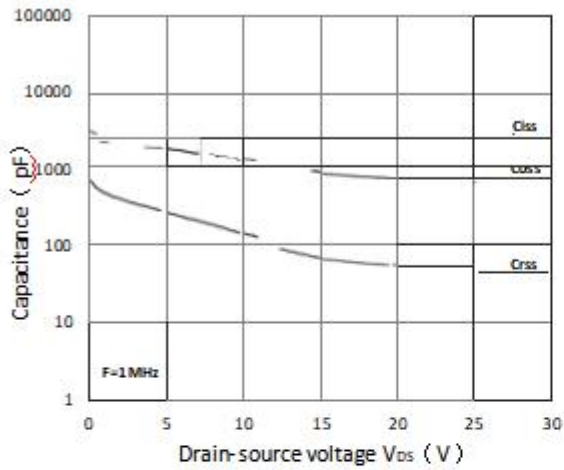


Figure 7. Capacitance Characteristics

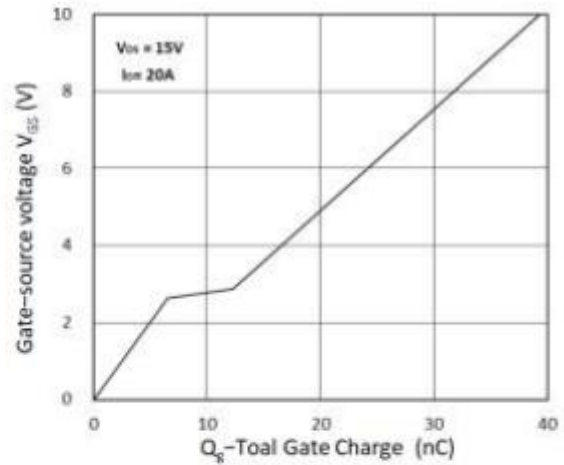


Figure 8. Gate Charge Characteristics

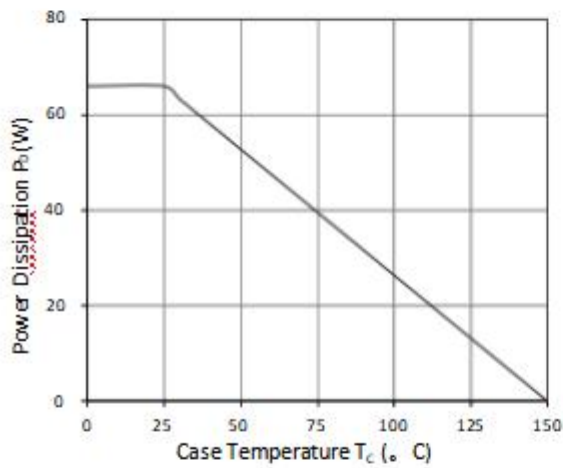


Figure 9. Power Dissipation

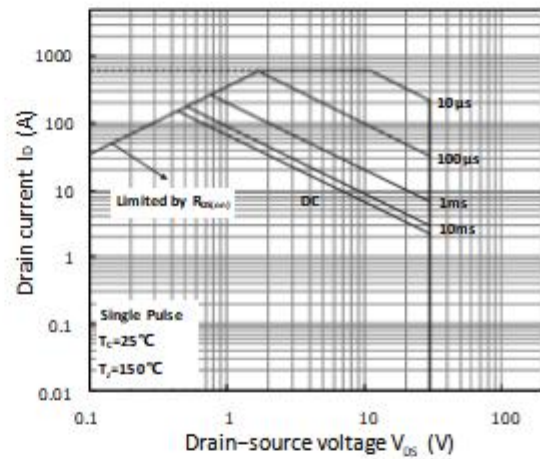


Figure 10. Safe Operating Area

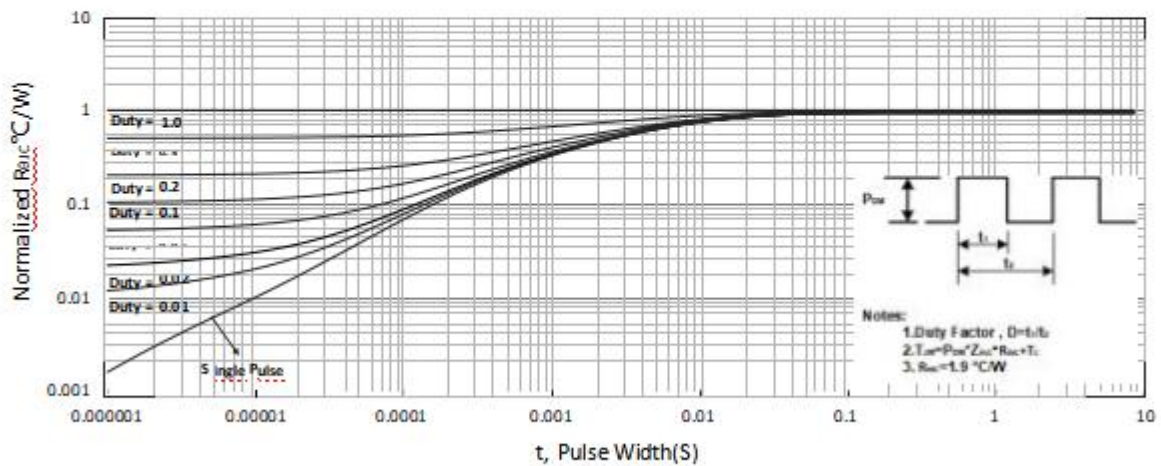


Figure 11. Normalized Maximum Transient Thermal Impedance

Test Circuit

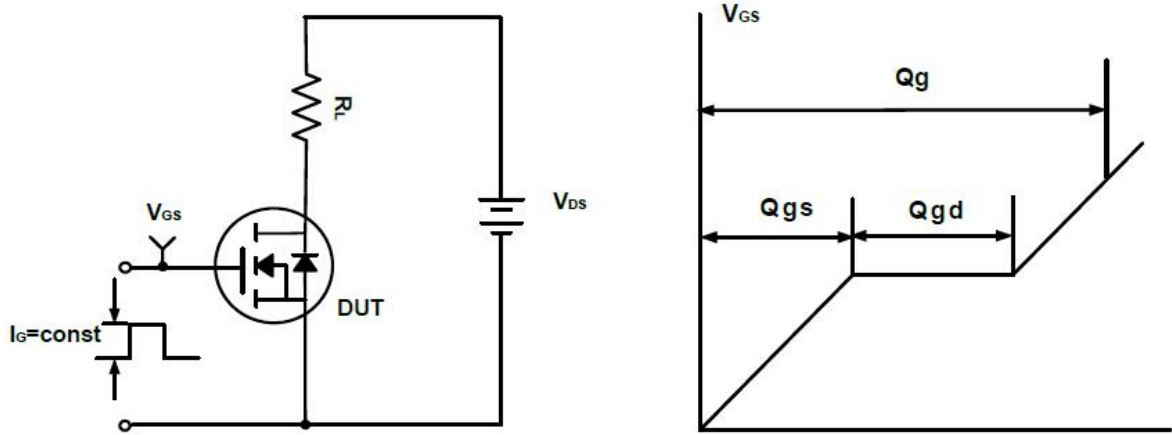


Figure A. Gate Charge Test Circuit & Waveforms

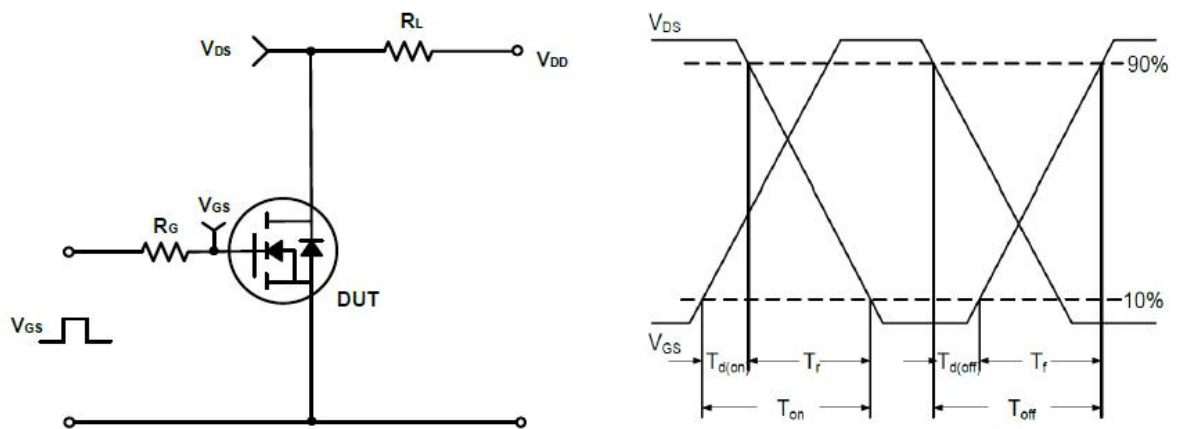


Figure B. Switching Test Circuit & Waveforms

Test Circuit

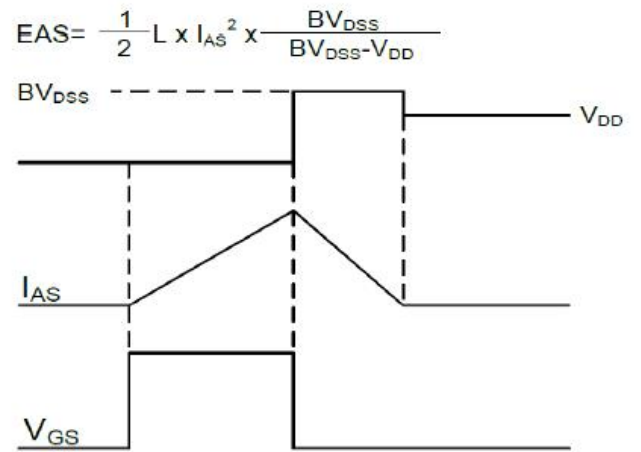
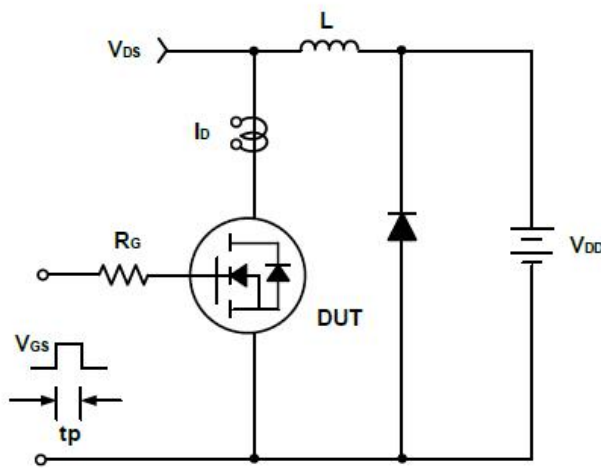
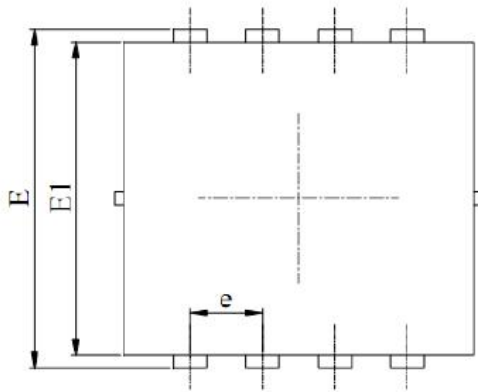


Figure C. Unclamped Inductive Switching Circuit & Waveforms

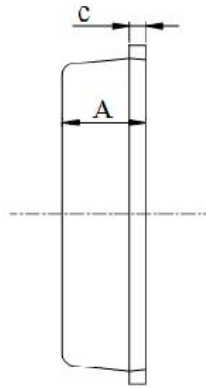


Package Dimensions

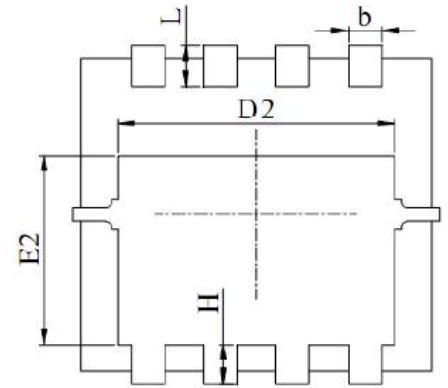
➤ PDFN3\*3-8L



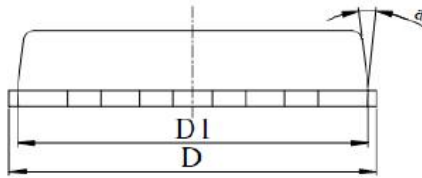
Top View



Side View



Bottom View

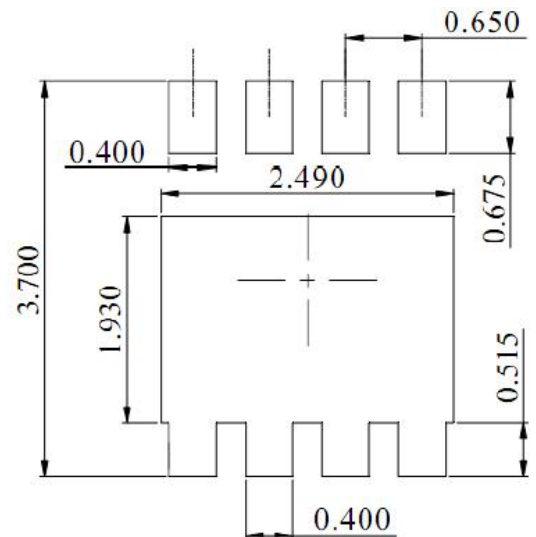


Front View

NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M,1994.
2. ALL DIMNESIONS IN MILLIMETER (ANNGLE IN DEGREE).
3. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

DIM.	MILLIMETER		
	MIN.	NOM.	MAX.
A	0.70	0.75	0.80
b	0.25	0.30	0.35
c	0.10	0.20	0.25
D	3.00	3.15	3.25
D1	2.95	3.05	3.15
D2	2.39	2.49	2.59
E	3.20	3.30	3.40
E1	2.95	3.05	3.15
E2	1.70	1.80	1.90
e	0.65 BSC		
H	0.30	0.40	0.50
L	0.25	0.40	0.50
a	---	---	15°



DIMENSIONS:MILLIMETERS





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[DMNH15H110SK3-13](#) [SLF10N65ABV2](#) [BSO203SP](#) [BSO211P](#)